

Supporting R&D, Process Control of Thin Films

Leading With Innovation

Sequential Wavelength-Dispersive X-ray Fluorescence Spectrometer

Thickness and composition measurements with analytical flexibility for R&D and small-batch processing



For all Elements from Be through U

- Auto loader for 300mm FOUP and 200mm open cassette available
- CCD camera for measurement point viewing
- Minimum measurement spot 500 μ m diameter
- Mapping measurement capabilities
- Possible to measure large samples up to 400mm diameter, 50mm thick, and 30kg
- Fundamental Parameters software ideal for complicated multi-layer stacks (MRAM, magnetic media, etc.)